

	ATTY. DOCKET NO.:	APPLICATION NO.:
	4717-8100	
	APPLICANT:	
	Laurent FILIPOZZI et al	
FILING DATE:	GROUP:	

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
AA		5,996,594	12/1999	Roy et al.	134	1.3	
AB		6,336,945 B1	1/2002	Yamamoto et al.	51	309	
AC							
AD							
AE							

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AF							
	AG							
	AH							
	AI							

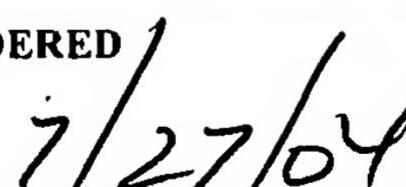
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	BD	
	BE	
	BF	

EXAMINER



DATE CONSIDERED



*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

		ATTY. DOCKET NO.:	APPLICATION NO.:
		4717-8100	10/621, 122
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July 15, 2003	3723		

U.S. PATENT DOCUMENTS

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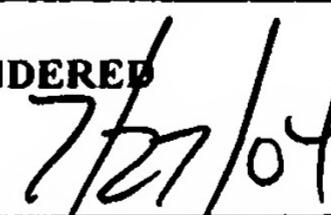
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AJ	Michael L. Free, XP-002266271, "Using Surfactants in iron-based CMP slurries to minimize residual particles", Surface Chemistries, Micromagazine (1998)
	AK	
	AL	

EXAMINER



DATE CONSIDERED

 7/27/04

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